



Camtek Launches NanoProf® at SEMICON Taiwan 2026



Camtek will unveil **NanoProf®** - its next-generation multi-sensor metrology platform for advanced packaging, at SEMICON Taiwan 2026.

NanoProf® combines the latest optical metrology sensors and AI-enhanced analytics to deliver high-precision nanoscale measurements. The platform supports Wafer Geometry, Post-CMP Nano-Topography, TSV, Thin-Film and Overlay Measurement on advanced packaging structures.

Visit Camtek at Booth M0938 to experience NanoProf® and Camtek's latest inspection and metrology innovations.

Technical Presentation

AI-Enhanced Metrology for Heterogeneous Integration

Dr. Roy Pinhassi | Heterogeneous Integration Global Summit 2026, Day 3

Learn how AI-powered algorithms are extending metrology capabilities to address the growing complexity of advanced packaging and heterogeneous integration.